



# Test and Reliability of Electronic Circuits in Natural and Radiative Environment

Luigi Dilillo

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**HABILITATION À DIRIGER DES  
RECHERCHES**

**Test and Reliability of Electronic Circuits in  
Natural and Radiative Environment**

Rapport de

**Luigi DILILLO**

Chargé de Recherche au C.N.R.S.

Mai 2015

# Preamble

The researches presented in this manuscript were performed between 2002 and 2015 at the laboratory LIRMM of Montpellier (France), the University of Southampton (ECS department) and the laboratory CEA LFSE of Saclay (France). This document consists of two main parts:

- The first part is an extended Curriculum Vitae, which includes details like collaborations, supervision, teaching activities, contracts, etc.
- The second part is a summary of my research activities and perspectives ending with bibliography references and the list of my publications.

The references of which I am not the author are indicated with a number that follows the order of appearance in the text. For example, [1] and [7] denote the first and the seventh publications that are referred in the document.

A different numbering was adopted to distinguish the work to which I contributed: publications in international journals are referenced by [JO#]; publications in international conferences, symposia and workshops are referenced by [CO#], [SY#] and [WO#] respectively.

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## **Table of Contents**

A.1.	CURRICULUM VITAE .....	3
A.1.1.	Supervision of Students and Teaching activities .....	4
A.1.1.1.	Thesis Supervision .....	4
A.1.1.2.	Postdoc Supervision .....	5
A.1.1.3.	Supervision of Master and Engineering Students .....	6
A.1.1.4.	Teaching Activities at University of Montpellier .....	6
A.1.2.	academic and industrial collaborations, technology transfer .....	7
A.1.2.1.	Contacts with the Scientific Community and the Industry .....	7
A.1.2.2.	Participation To Research Contracts .....	9
A.1.3.	Coordination, Support and management of researches .....	9
A.1.3.1.	Member of Committee of International Conferences .....	9
A.1.3.2.	Member of Committee of National Conferences .....	10
A.1.3.3.	Session Chair in International Conferences .....	10
A.1.3.4.	Member of the Board of Scientific Organizations .....	11
A.1.3.5.	Organization of Sessions in International Conferences .....	11
A.1.3.6.	Reviewer Activity .....	11
A.2.	Summary of my Scientific Researches .....	13
A.2.1.	Context .....	13
A.2.2.	Basics of Test of Integrated Circuits and Systems, Radiation Test and Monitoring .....	14
A.2.2.1.	The Role of Test .....	14
A.2.2.2.	Types And Techniques Of Test .....	14
A.2.3.	Radiation Test and Radiation Monitoring .....	16
A.3.	Detail Of My Scientific Activity .....	19
A.3.1.	Test of Dynamic Faults in SRAM Memories .....	19
A.3.1.1.	Summary of the Studies on Dynamic Faults in SRAMs .....	26
A.3.2.	Low Power Test of Digital Circuits and Memories .....	28
A.3.3.	Impact of Radiation on Digital Circuits .....	32
A.3.3.1.	Basic Mechanisms of Soft Errors .....	33
A.3.3.2.	Proposed Framework For Simulation Level Testing Testing of Radiation Effects .....	35
A.3.3.3.	Accelerated test .....	37
A.3.4.	Radiation Monitoring .....	42
A.3.4.1.	SRAM Based Monitor for Mixed-Field Radiation Environments .....	43
A.3.4.2.	Real-Time Testing of 90nm COTS SRAMs at Concordia Station in Antarctica .....	45
A.3.5.	Space and Radiation Hardened Systems Design .....	48
A.4.	Research Perspectives .....	50
A.4.1.	Monitoring of High Temperature Effects of CMOS Circuits .....	50
A.4.2.	Design and Characterization of Radiation-Hardened Front-end Electronic Systems .....	50
A.4.3.	Test and Reliability of Low Power SRAM Memories in Deep nanoscale technology .....	51
A.4.4.	Medium and Long Term Plans .....	52
A.5.	Personal publications .....	53
A.6.	Bibliography .....	62